

DIE-LEVEL PROBER

Abstract

A die-level prober for testing an unpackaged liquid crystal on silicon (LCOS) display panel includes a tray and a probe card. The unpackaged LCOS display panel has at least a first contact pad and a second contact pad. Additionally, the tray includes at least a recession for situating the unpackaged LCOS display panel, and a conductive connecting structure electrically contacting the first contact pad. The probe card is utilized to electrically contact the connecting structure and the second contact pad for testing the unpackaged LCOS display panel.